

SIGC14T60SNC

IGBT Chip in NPT-technology

FEATURES:

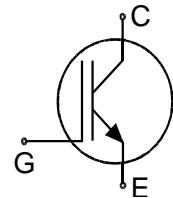
- 600V NPT technology
- 100µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

This chip is used for:

- SGP15N60

Applications:

- drives



Chip Type	V _{CE}	I _{Ch}	Die Size	Package	Ordering Code
SIGC14T60SNC	600V	15A	3.8 x 3.8 mm ²	sawn on foil	Q67041-A4665-A001
SIGC14T60SNC	600V	15A	3.8 x 3.8 mm ²	unsawn	Q67041-A4665-A002

MECHANICAL PARAMETER:

Raster size	3.8 x 3.8	mm ²
Area total / active	14.44 / 10.7	
Emitter pad size	1.89 x 2.19	
Gate pad size	0.7 x 1.09	
Thickness	100	µm
Wafer size	150	mm
Flat position	270	deg
Max.possible chips per wafer	1032	
Passivation frontside	Photoimide	
Emitter metallization	3200 nm Al Si 1%	
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding	
Die bond	electrically conductive glue or solder	
Wire bond	Al, ≤500µm	
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm	
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month	

MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V_{CE}	600	V
DC collector current, limited by T_{jmax}	I_C	31	A
Pulsed collector current, t_p limited by T_{jmax}	I_{cpuls}	62	A
Gate emitter voltage	V_{GE}	± 20	V
Operating junction and storage temperature	T_j, T_{stg}	-55 ... +150	°C

STATIC CHARACTERISTICS (tested on chip), $T_j=25$ °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-emitter breakdown voltage	$V_{(BR)CES}$	$V_{GE}=0V, I_C=500\mu A$	600			
Collector-emitter saturation voltage	$V_{CE(sat)}$	$V_{GE}=15V, I_C=15A$	1.6	2	2.5	V
Gate-emitter threshold voltage	$V_{GE(th)}$	$I_C=400\mu A, V_{GE}=V_{CE}$	3	4	5	
Zero gate voltage collector current	I_{CES}	$V_{CE}=600V, V_{GE}=0V$			70	μA
Gate-emitter leakage current	I_{GES}	$V_{CE}=0V, V_{GE}=30V$			120	nA

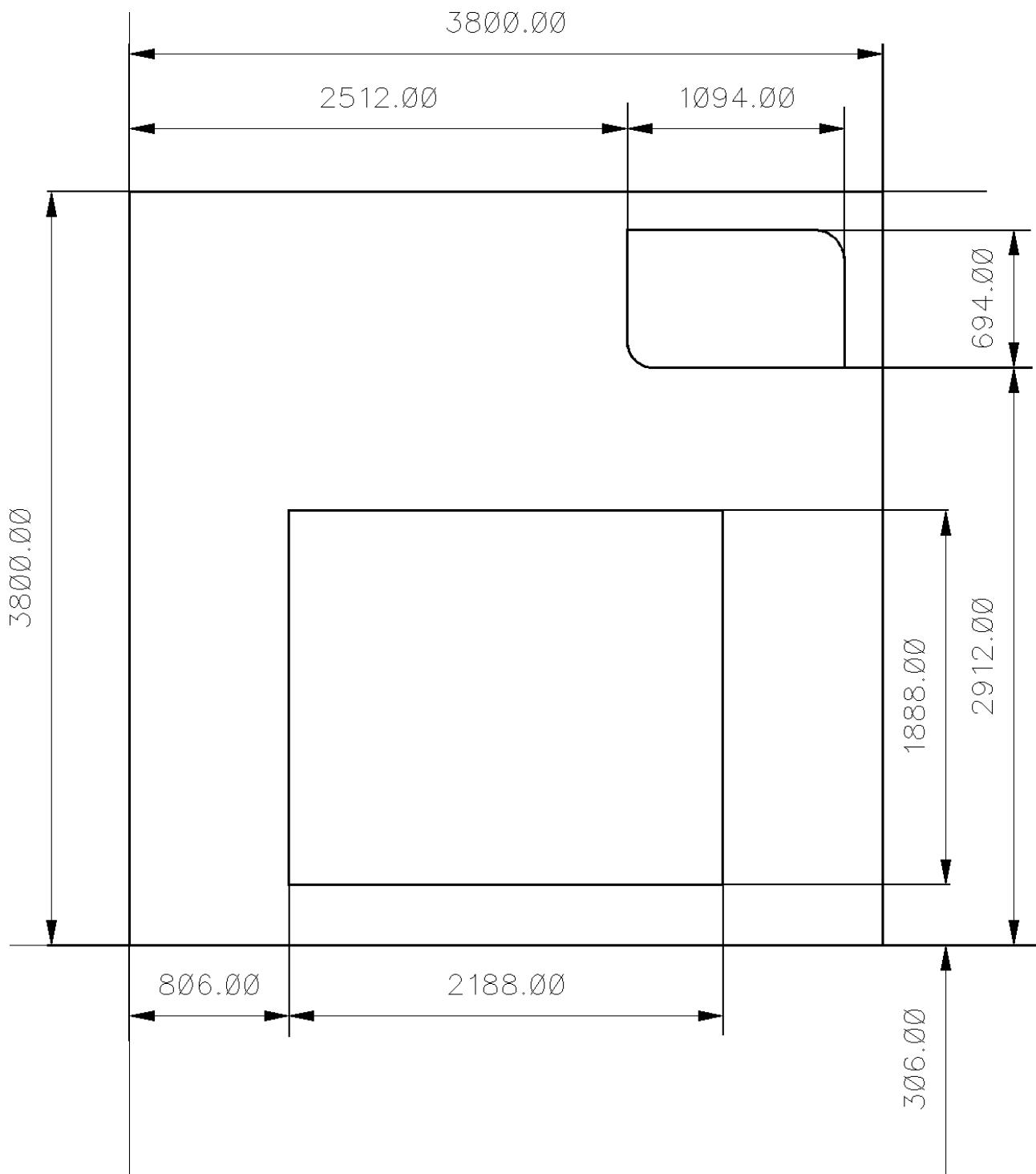
DYNAMIC CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Input capacitance	C_{iss}	$V_{CE}=25V$	-	800	960	pF
Output capacitance	C_{oss}	$V_{GE}=0V$	-	84	100	
Reverse transfer capacitance	C_{rss}	$f=1MHz$	-	52	63	

SWITCHING CHARACTERISTICS (tested at component), Inductive Load:

Parameter	Symbol	Conditions*	Value			Unit
			min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	$T_j=150$ °C $V_{CC}=400V$ $I_C=15A$ $V_{GE}=+15/0V$ $R_G=21\Omega$	-	31	38	ns
Rise time	t_r		-	23	28	
Turn-off delay time	$t_{d(off)}$		-	261	313	
Fall time	t_f		-	54	65	

* switching conditions different to 600V LowLoss, under comparable switching conditions 40% faster turnoff than LowLoss

CHIP DRAWING:



FURTHER ELECTRICAL CHARACTERISTICS:

This chip data sheet refers to the
device data sheet

SGP15N60

Package :TO220

Description:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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